Search Notes			

Application/Control No.	Applicant(s)/Patent unde Reexamination	Applicant(s)/Patent under Reexamination	
10/780,579	ONOZAWA ET AL.		
Examiner	Art Unit		
Leith A. Al-Nazer	2821		

	SEARCHED			
Class	Subclass	Date	Examiner	
315	169.1- 169.4	4/13/2006	LA	
345	55, 60	4/13/2006	LA	
345	204	4/13/2006	LA	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Jpdated EAST prior art text search see "Examiner Search Notes")	4/13/2006	LA